

## EPITAXIAL GROWTH OF CIGSE LAYERS ON GaP/Si(001) PSEUDO-SUBSTRATE FOR TANDEM CIGSE/Si SOLAR CELLS

**Reference:** *Solar Energy Materials and Solar Cells* 233, 111385, 2021

**Collaborations :** IMN, Institut FOTON, UMR-IPVF

**DOI :** <https://doi.org/10.1016/j.solmat.2021.111385>

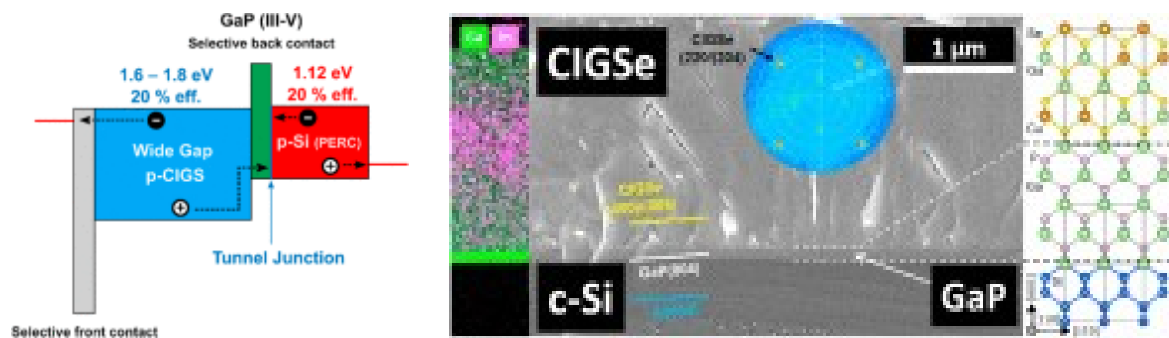
**Contacts:**

N. Barreau (IMN) : [nicolas.barreau@univ-nantes.fr](mailto:nicolas.barreau@univ-nantes.fr)

O. Durand (Institut FOTON): [Olivier.Durand@insa-rennes.fr](mailto:Olivier.Durand@insa-rennes.fr)

D. Lincot (UMR-IPVF): [daniel.lincot@cnrs.fr](mailto:daniel.lincot@cnrs.fr)

The paper reports on the investigation of the epitaxial growth of co-evaporated Cu(In,Ga)Se<sub>2</sub> films (CIGSe) onto GaP/Si(001) pseudo- substrates, where the GaP thin layer is epitaxially grown by Molecular Beam Epitaxy (MBE). Extensive structural characterization of epi-CIGSe is carried out via X-ray diffraction and transmission electron microscopy. Sturdy evidence of an epitaxial growth of CIGSe on (GaP/Si)(001) is observed, with the propagation of twins originating from the GaP/Si interface, through the CIGSe/GaP interface. This work aims at paving the way for future CIGSe/GaP/Si structures for the development of tandem solar cells with a c-Si bottom cell, and a GaP interfacial buffer layer for band edge engineering, allowing for the monolithic epitaxial growth of high quality CIGSe as a thin film cell absorber.



*Left: Band structure of the targeted tandem device structure*

*Right: scanning electron microscopy image of c-Si/GaP/CIGSe cross section and main advanced X-Ray diffraction and transmission electron microscopy investigations.*